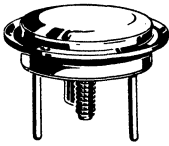


# 2N4048 thru 2N4053 (GERMANIUM)



**CASE 7**

PNP germanium power transistors designed for high-current applications requiring high gain and extremely low saturation voltage.

Collector connected to case

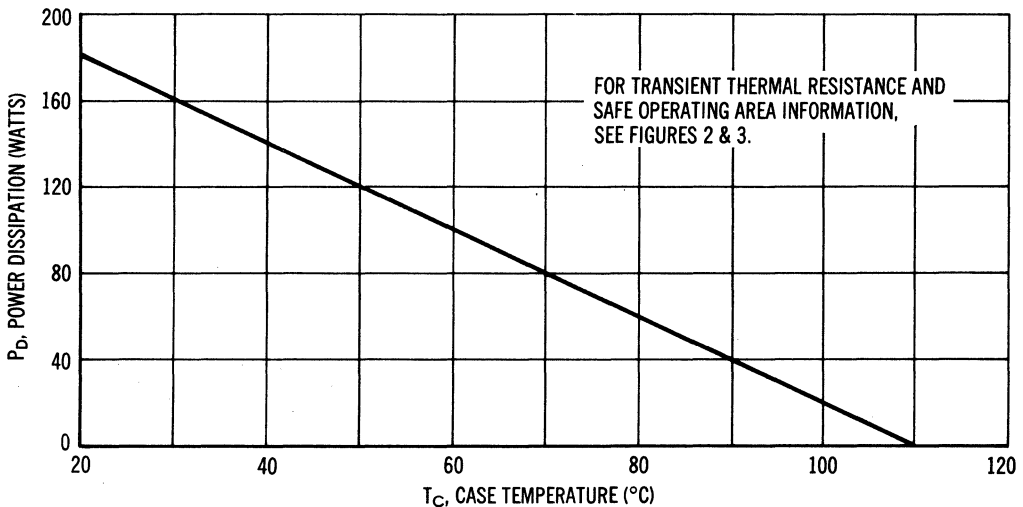
## MAXIMUM RATINGS

Rating	Symbol	2N4048 2N4051	2N4049 2N4052	2N4050 2N4053	Unit
Collector-Emitter Voltage	$V_{CEO}$	30	45	60	Vdc
Collector-Emitter Voltage	$V_{CES}$	45	60	75	Vdc
Collector-Base Voltage	$V_{CB}$	45	60	75	Vdc
Emitter-Base Voltage	$V_{EB}$	25	30	40	Vdc
Collector Current – Continuous	$I_C^*$	← 60 →			Adc
Total Device Dissipation @ $T_C = 25^\circ\text{C}$	$P_D$	← 170 →			Watts
Derate above $25^\circ\text{C}$		← 2.0 →			W/ $^\circ\text{C}$
Operating and Storage Junction Temperature Range	$T_J, T_{stg}$	← -65 to +110 →			$^\circ\text{C}$

## THERMAL CHARACTERISTICS

Characteristic	Symbol	Max	Unit
Thermal Resistance, Junction to Case	$\theta_{JC}$	← 0.5 →	$^\circ\text{C}/\text{W}$

**FIGURE 1 — AVERAGE POWER-TEMPERATURE DERATING CURVE**



\* JEDEC Registered Values, For True Capability See Figure 3

# 2N4048 thru 2N4053 (continued)

## ELECTRICAL CHARACTERISTICS (T<sub>c</sub> = 25°C unless otherwise noted)

Characteristic	Symbol	Min	Max	Unit
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### OFF CHARACTERISTICS

Collector-Emitter Breakdown Voltage † (I <sub>C</sub> = 1.0 Adc, I <sub>B</sub> = 0)	2N4048, 2N4051 2N4049, 2N4052 2N4050, 2N4053	BV <sub>CEO</sub> †	30 45 60	- - -	Vdc
Collector-Emitter Breakdown Voltage (I <sub>C</sub> = 300 mAdc, V <sub>BE</sub> = 0)	2N4048, 2N4051 2N4049, 2N4052 2N4050, 2N4053	BV <sub>CES</sub>	45 60 75	- - -	Vdc
Floating Potential (V <sub>CB</sub> = 45 Vdc, I <sub>E</sub> = 0)	2N4048, 2N4051	V <sub>EBF</sub>	-	0.5	Vdc
(V <sub>CB</sub> = 60 Vdc, I <sub>E</sub> = 0)	2N4049, 2N4052		-	0.5	
(V <sub>CB</sub> = 75 Vdc, I <sub>E</sub> = 0)	2N4050, 2N4053		-	0.5	
Collector Cutoff Current (V <sub>CE</sub> = 30 Vdc, V <sub>BE(off)</sub> = 2.0 Vdc, T <sub>C</sub> = +71°C)	2N4048, 2N4051	I <sub>CEX</sub>	-	15	mAdc
(V <sub>CE</sub> = 45 Vdc, V <sub>BE(off)</sub> = 2.0 Vdc, T <sub>C</sub> = +71°C)	2N4049, 2N4052		-	15	
(V <sub>CE</sub> = 60 Vdc, V <sub>BE(off)</sub> = 2.0 Vdc, T <sub>C</sub> = +71°C)	2N4050, 2N4053		-	15	
Collector Cutoff Current (V <sub>CB</sub> = 2.0 Vdc, I <sub>E</sub> = 0)		I <sub>CBO</sub>	-	0.2	mAdc
(V <sub>CB</sub> = 45 Vdc, I <sub>E</sub> = 0)	2N4048, 2N4051		-	4.0	
(V <sub>CB</sub> = 60 Vdc, I <sub>E</sub> = 0)	2N4049, 2N4052		-	4.0	
(V <sub>CB</sub> = 75 Vdc, I <sub>E</sub> = 0)	2N4050, 2N4053		-	4.0	
Emitter Cutoff Current (V <sub>BE</sub> = 25 Vdc, I <sub>C</sub> = 0)	2N4048, 2N4051	I <sub>EBO</sub>	-	4.0	mAdc
(V <sub>BE</sub> = 25 Vdc, I <sub>C</sub> = 0, T <sub>C</sub> = +71°C)			-	15	
(V <sub>BE</sub> = 30 Vdc, I <sub>C</sub> = 0)	2N4049, 2N4052		-	4.0	
(V <sub>BE</sub> = 30 Vdc, I <sub>C</sub> = 0, T <sub>C</sub> = +71°C)			-	15	
(V <sub>BE</sub> = 40 Vdc, I <sub>C</sub> = 0)	2N4050, 2N4053		-	4.0	
(V <sub>BE</sub> = 40 Vdc, I <sub>C</sub> = 0, T <sub>C</sub> = +71°C)			-	15	

### ON CHARACTERISTICS

DC Current Gain † (I <sub>C</sub> = 15 Adc, V <sub>CE</sub> = 2.0 Vdc)	2N4048, 2N4049, 2N4050 2N4051, 2N4052, 2N4053	h <sub>FE</sub> †	60 120 15	180 240 -	-
(I <sub>C</sub> = 60 Adc, V <sub>CE</sub> = 2.0 Vdc)					
Collector-Emitter Saturation Voltage † (I <sub>C</sub> = 15 Adc, I <sub>B</sub> = 1.0 Adc)		V <sub>CE(sat)</sub> †	-	0.15	Vdc
(I <sub>C</sub> = 60 Adc, I <sub>B</sub> = 6.0 Adc)			-	0.3	
Base-Emitter Saturation Voltage † (I <sub>C</sub> = 15 Adc, I <sub>B</sub> = 1.0 Adc)		V <sub>BE(sat)</sub> †	-	0.6	Vdc
(I <sub>C</sub> = 60 Adc, I <sub>B</sub> = 6.0 Adc)			-	1.0	

### SMALL SIGNAL CHARACTERISTICS

Common-Emitter Cutoff Frequency (I <sub>C</sub> = 15 Adc, V <sub>CE</sub> = 2.0 Vdc)	f <sub>αe</sub>	2.0	-	kHz
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† To avoid excessive heating of the collector junction, perform test with pulse method.

The switching performance of this transistor is determined primarily by the gain-bandwidth product, f<sub>t</sub>\*, and the behavior of the base-spreading resistance, r<sub>b</sub>'.

In the case of rise time, the base-spreading resistance plays a small part, and the test circuit delivers a constant current step of turn-on current to the transistor (I<sub>B1</sub>). Therefore, the curve of t<sub>r</sub> on Figure 6 follows theory closely, i.e.:

$$t_r = 0.8 \frac{I_C}{I_{B1}} \cdot \frac{1}{2\pi f_t}$$

From the curve, it can be seen that f<sub>t</sub> is roughly constant with current; using the equation, its large signal value can be calculated to be approximately 120 kHz at the 20-Amp level. A lower supply voltage will increase rise time slightly.

Turn-off time is slow because of conductivity modulation which occurs in the base region. When the transistor is held "on" in saturation, the base region becomes filled with excess charge; i.e., charge in excess of that

\* f<sub>t</sub> = f<sub>αe</sub> × h<sub>FE</sub>

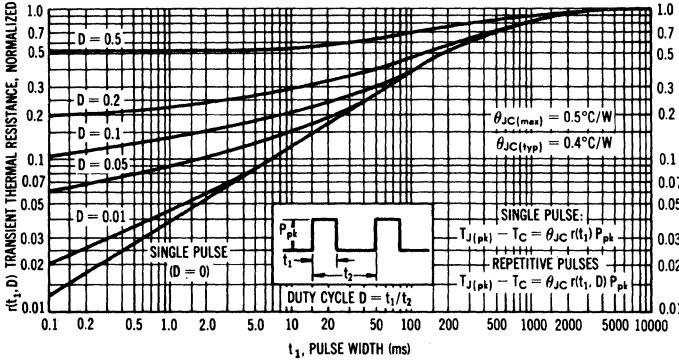
necessary to sustain the circuit limited value of I<sub>C</sub>. As a result, the base resistivity and consequently r<sub>b</sub>' become very low. During turn off, as the excess charge is reduced, the accompanying increase in resistivity causes a marked reduction in the turn-off current, I<sub>B2</sub>, as can be seen from the waveforms of Figure 5. During fall time, the I<sub>B2</sub> current is very low causing an extended fall time.

Only a slight improvement in turn-off performance is achieved with a "speed up" capacitor placed across R<sub>B</sub>. This unusual behavior occurs because r<sub>b</sub>' limits the amount of reverse current which can be achieved. Also, it seems evident that r<sub>b</sub>' increases with applied reverse current, so that efforts to speed up the turn-off behavior are somewhat futile.

In most applications, switching time will be close to the values shown on Figure 6. Delay time is not shown as it is negligible in comparison to the other times.

2N4048 thru 2N4053 (continued)

FIGURE 2 — TRANSIENT THERMAL RESISTANCE



There are two limitations on the power handling ability of a transistor: junction temperature and secondary breakdown. Safe operating area curves indicate  $I_C$ - $V_{CE}$  limits of the transistor that must be observed for reliable operation; i.e. the transistor must not be subjected to greater dissipation than the curves indicate.

The data of Figure 3 is based on  $T_{J(pk)} = 110^\circ\text{C}$ ;  $T_C$  is variable depending upon conditions. Pulse curves are valid for duty cycles to 10% provided  $T_{J(pk)} < 110^\circ\text{C}$ .  $T_{J(pk)}$  may be calculated from the data in Figure 2. At high case temperatures, thermal limitations will reduce the power that can be handled to values less than the limitations imposed by secondary breakdown.

FIGURE 3 — ACTIVE REGION SAFE-OPERATING AREA

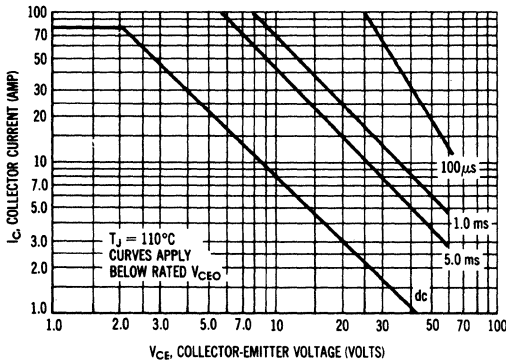


FIGURE 4 — SAFE OPERATING AREA TEST CIRCUIT

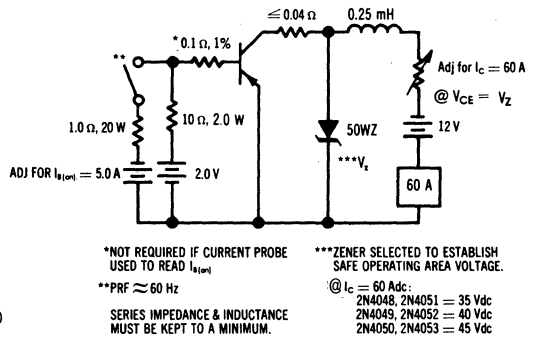


FIGURE 5 — SWITCHING TEST CIRCUIT

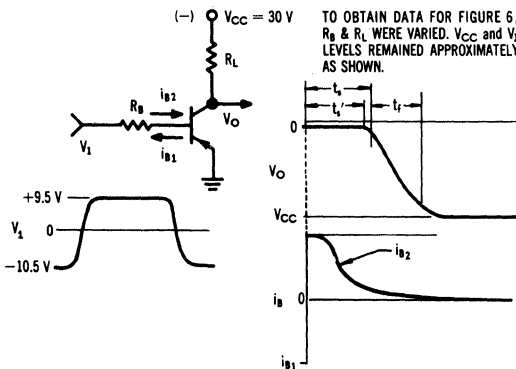
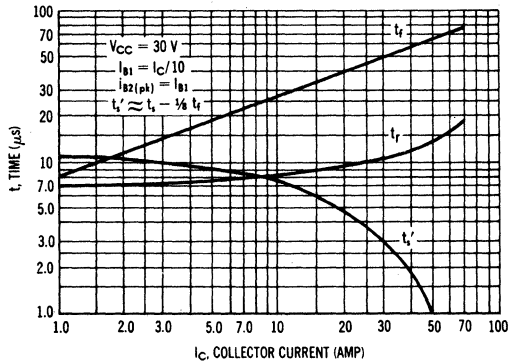


FIGURE 6 — SWITCHING TIMES



2N4048 thru 2N4053 (continued)

TYPICAL DC CHARACTERISTICS

FIGURE 7 — DC CURRENT GAIN

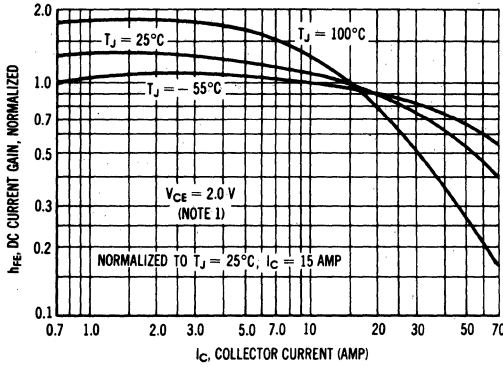


FIGURE 8 — COLLECTOR SATURATION REGION

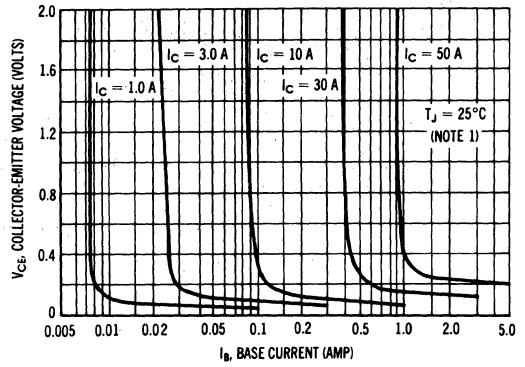


FIGURE 9 — EFFECTS OF BASE-EMITTER RESISTANCE

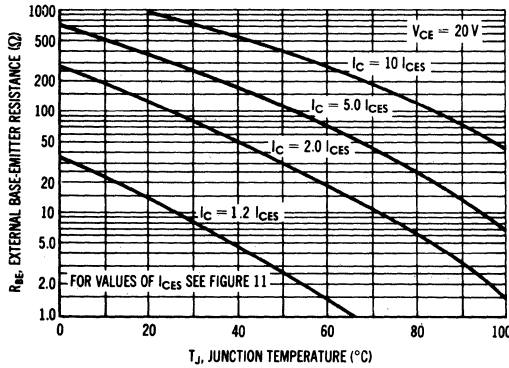


FIGURE 10 — "ON" VOLTAGES

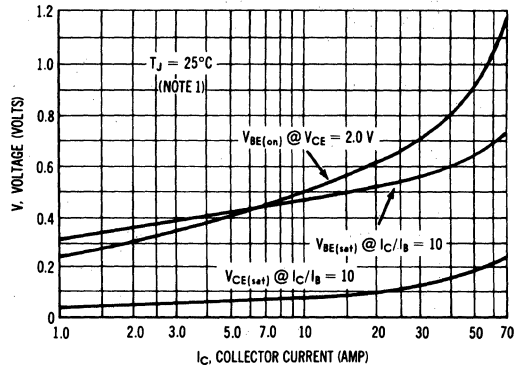


FIGURE 11 — COLLECTOR CUTOFF REGION

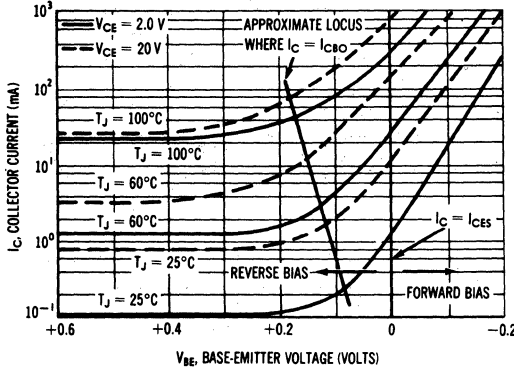
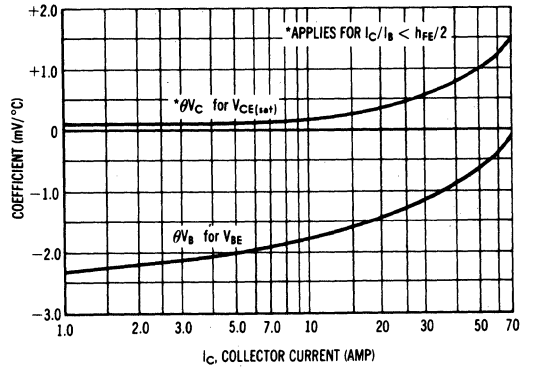


FIGURE 12 — TEMPERATURE COEFFICIENTS



NOTE 1: Data is obtained from pulse tests and adjusted to nullify the effect of  $I_{CBO}$ .